

# Resource Summary Report

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## FEI: Phenom Pro Desktop SEM

RRID:SCR\_019902

Type: Tool

### Proper Citation

FEI: Phenom Pro Desktop SEM (RRID:SCR\_019902)

### Resource Information

**URL:** <https://www.fei.com/products/sem/phenom-pro/>

**Proper Citation:** FEI: Phenom Pro Desktop SEM (RRID:SCR\_019902)

**Description:** Desktop scanning electron microscope with CeB6 source that offers high brightness while requiring low maintenance. It allows sample structures to be physically examined and their elemental composition determined.

**Resource Type:** instrument resource

**Keywords:** FEI, SEM, Instrument Equipment, USEDit,

**Availability:** Commercially available

**Resource Name:** FEI: Phenom Pro Desktop SEM

**Resource ID:** SCR\_019902

**Alternate IDs:** Model\_Number\_Phenom Pro

**Record Creation Time:** 20220129T080347+0000

**Record Last Update:** 20260912T195925+0000

### Ratings and Alerts

No rating or validation information has been found for FEI: Phenom Pro Desktop SEM.

No alerts have been found for FEI: Phenom Pro Desktop SEM.

### Data and Source Information

**Source:** [SciCrunch Registry](#)

## Usage and Citation Metrics

We have not found any literature mentions for this resource.